

Abstract Submitted  
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**Insulator-quantum Hall transition and Dirac fermion heating in low-carrier-density monolayer epitaxial graphene** LUNG-I HUANG<sup>1</sup>, YAN-FEI YANG<sup>2</sup>, RANDOLPH ELMQUIST, DAVID NEWELL, National Institute of Standards and Technology, CHI-TE LIANG, National Taiwan University — We present magneto-transport measurements on ungated, low-carrier-density epitaxial graphene Hall devices at low temperatures  $T$ . At  $T = 4.25$  K the carrier density and mobility of one device are  $1.38 \times 10^{11} \text{ cm}^{-2}$  and  $6500 \text{ cm}^2 \text{V}^{-1} \text{s}^{-1}$ , respectively. At low magnetic fields  $B$ , this device shows insulating behavior in the sense that the measured resistivity  $\rho_{xx}$  increases with decreasing  $T$ . A highly developed quantum Hall (QH) resistivity plateau  $\rho_{xy} \approx \frac{h}{2e^2}$  corresponding to a Landau-level filling factor  $\nu = 2$  in monolayer graphene can be observed at magnetic fields  $B \geq 1.5$  T. Between the low-field insulator regime and the  $\nu = 2$  QH state we observe a  $T$ -independent point in  $\rho_{xx}$  which corresponds to the insulator-quantum Hall (I-QH) transition. This transition, like those in semiconductor-based two-dimensional (2D) systems, can be also observed by increasing the driving current  $I$  at fixed ambient temperature. However, the measured  $\rho_{xx}$  at the I-QH transition is close to  $\frac{h}{4e^2}$ , rather than  $\frac{h}{2e^2}$  as expected by conventional I-QH theory. Furthermore,  $\rho_{xx}$  is substantially higher than  $\rho_{xy}$  at the crossing point. By using the zero-field resistivity and weak localization effect as two independent thermometers to determine effective Dirac fermion temperature ( $T_{DF}$ ) at various  $I$ , we find that  $T_{DF} \sim I^{0.5}$ , consistent with those obtained in various 2D systems.

<sup>1</sup>NIST and National Taiwan University

<sup>2</sup>NIST and Georgetown University

Randolph Elmquist  
NIST - Natl Inst of Stds & Tech

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